

ESE370: Circuit-Level Modeling, Design, and Optimization for Digital Systems

Lec 15: October 11, 2021
Energy and Power Basics

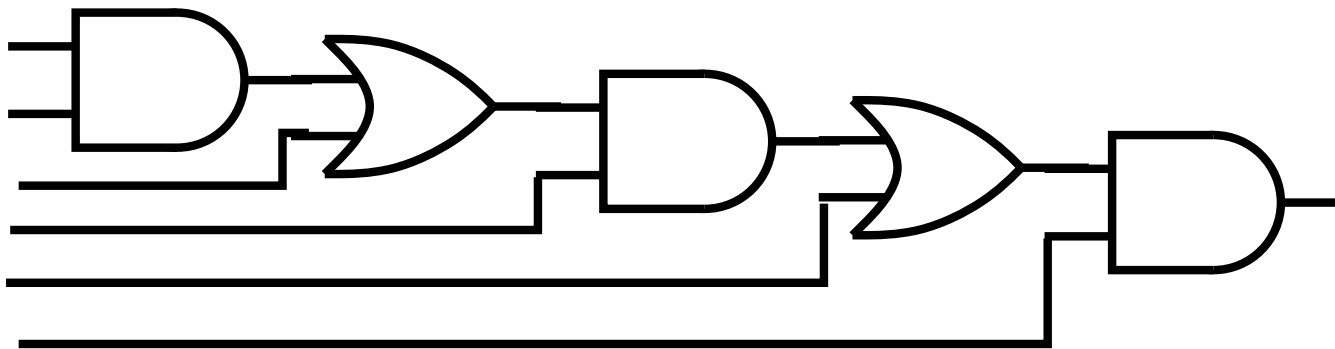


Previously

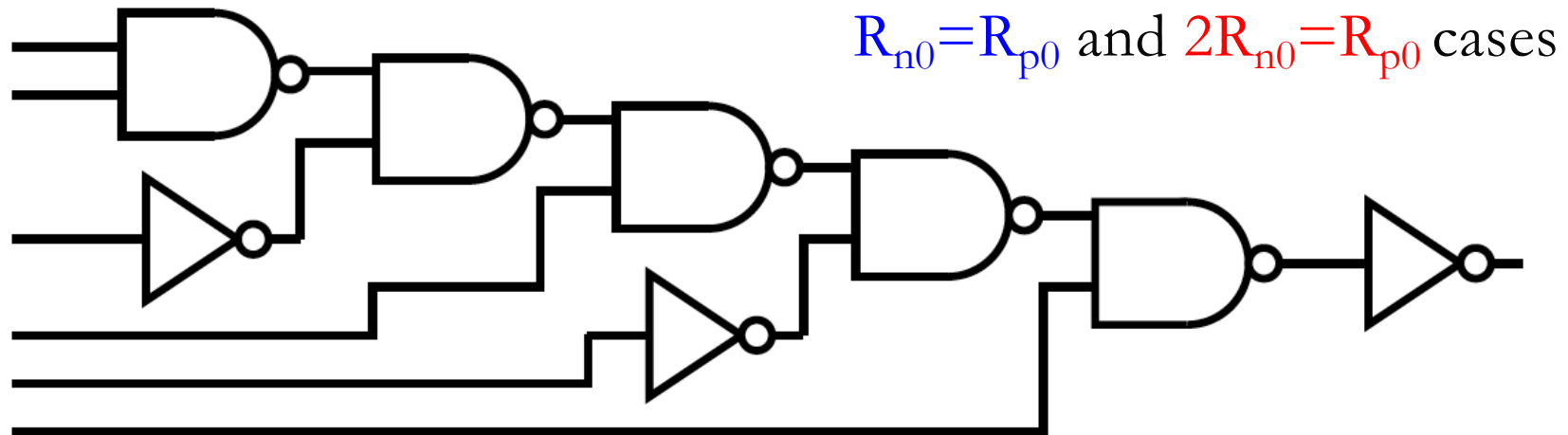
- Where capacitance arises
 - Device materials
- What drives delay
 - Equivalent drive resistance and load capacitance
- Optimize delay
 - τ -estimate
 - Transistor sizing
 - Fanin/fanout
 - Drive in stages



And-Or Chain

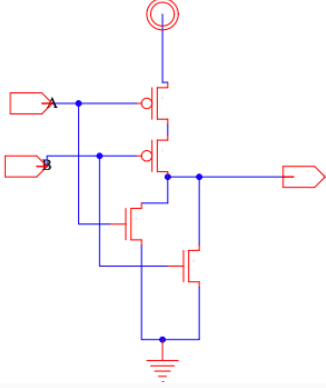


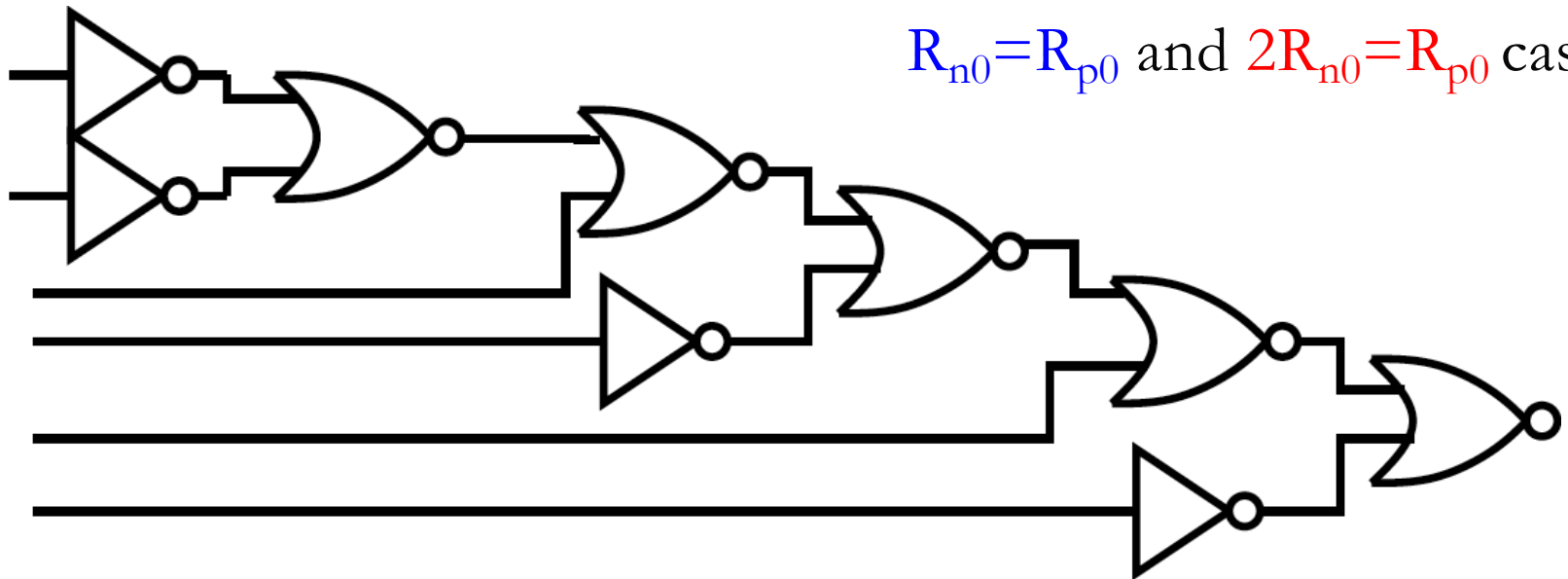
Delay of each implementation? (lec 14, preclass 4)



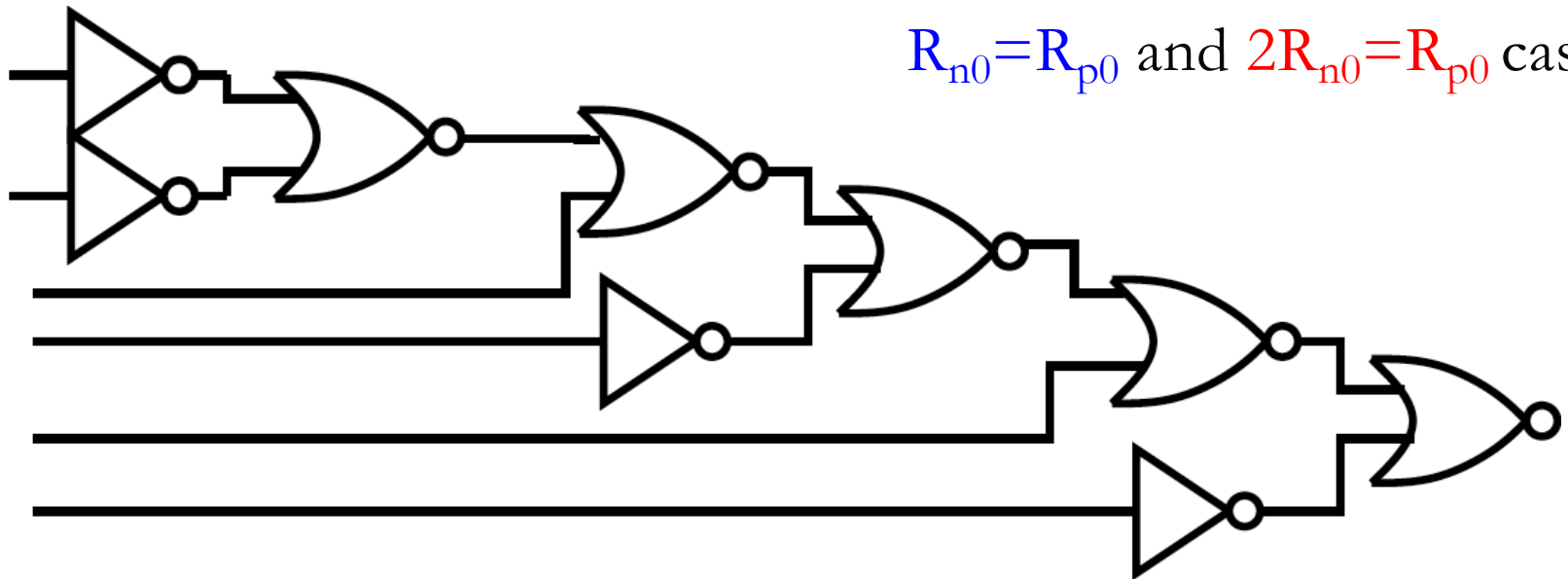
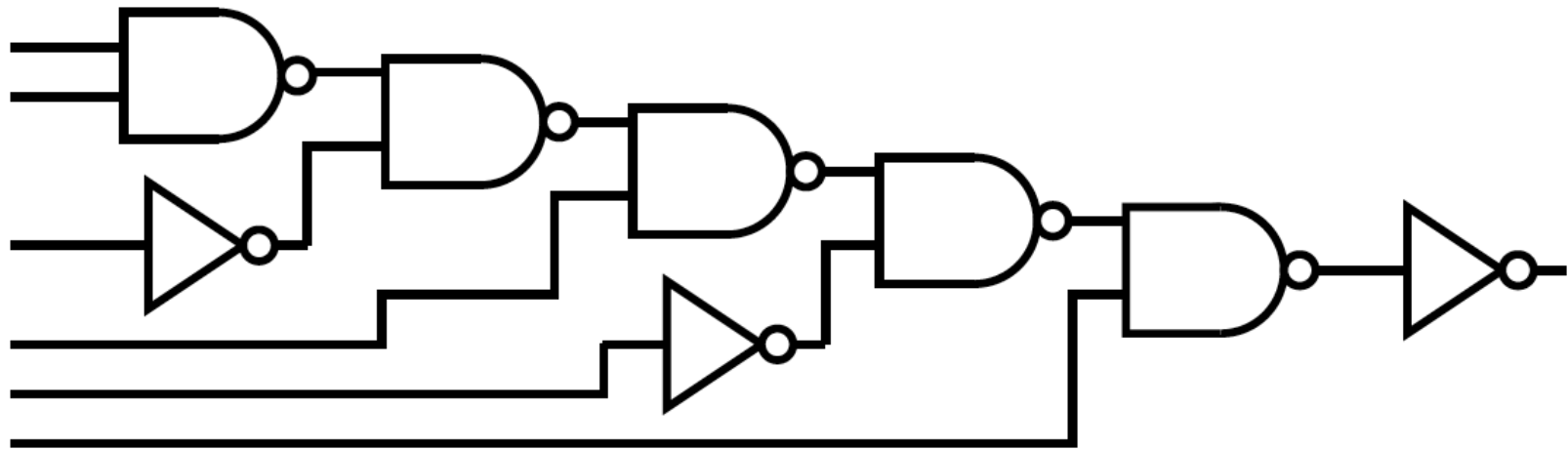
$R_{drive} = R_0/2$	$R_{p0} = R_{n0}$			$R_{p0} = 2R_{n0}$		
	W_p	W_n	C_a	W_p	W_n	C_a
	2	4	$6C_0$	4	4	$8C_0$

Delay of each implementation? (lec 14, preclass 4)

$R_{drive} = R_0/2$	$R_{p0} = R_{n0}$			$R_{p0} = 2R_{n0}$		
	W_p	W_n	C_a	W_p	W_n	C_a
	4	2	$6C_0$	8	2	$10C_0$



Delay of each implementation? (lec 14, preclass 4)

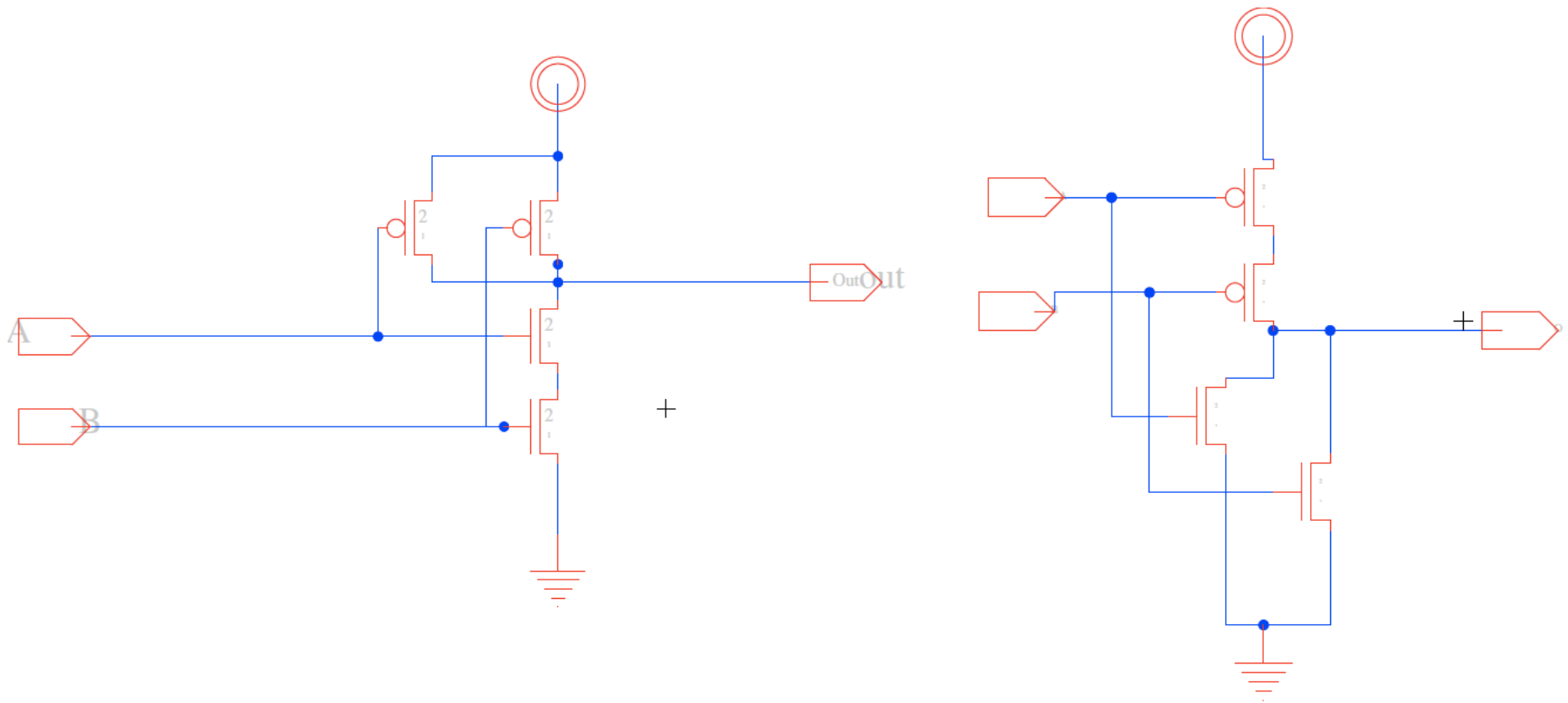


$R_{n0} = R_{p0}$ and $2R_{n0} = R_{p0}$ cases



Take Away?

- ❑ nor vs. nand





Today

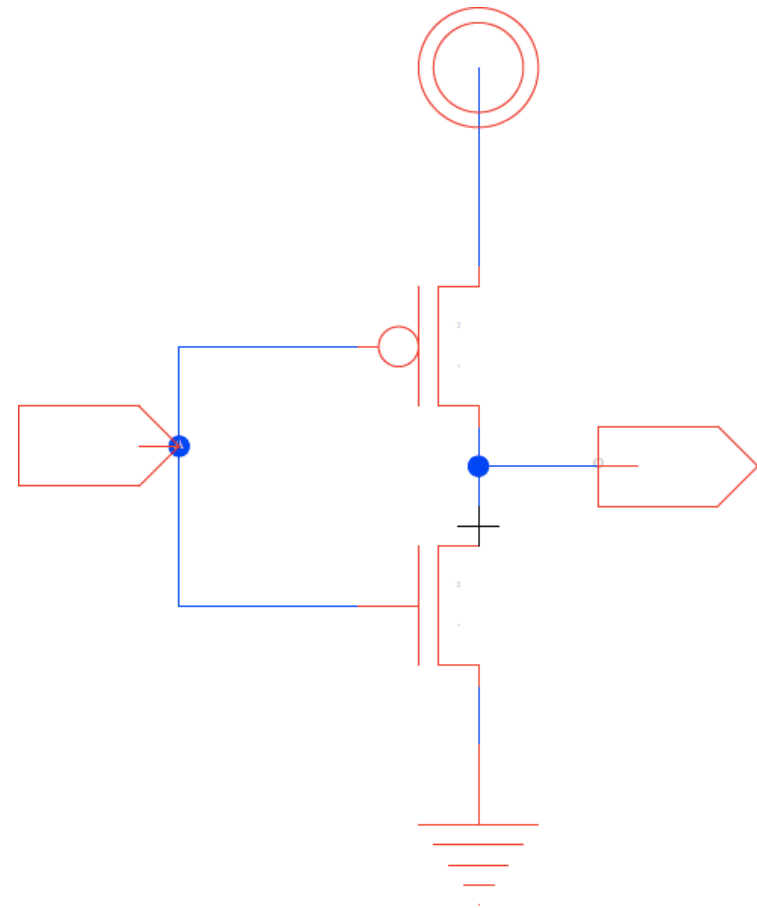
- Power Sources
 - Static power
 - Switching power
 - Dynamic switching power
 - Short circuit power (if time)



Power

- $P = I \times V$

- Tricky part:
 - Understanding I
 - (pairing with correct V)



Inverter Current Simplification (preclass)

□ What is $I_{\text{pwr,gnd}}$?

■ 0V

■ 140mV

■ 400mV

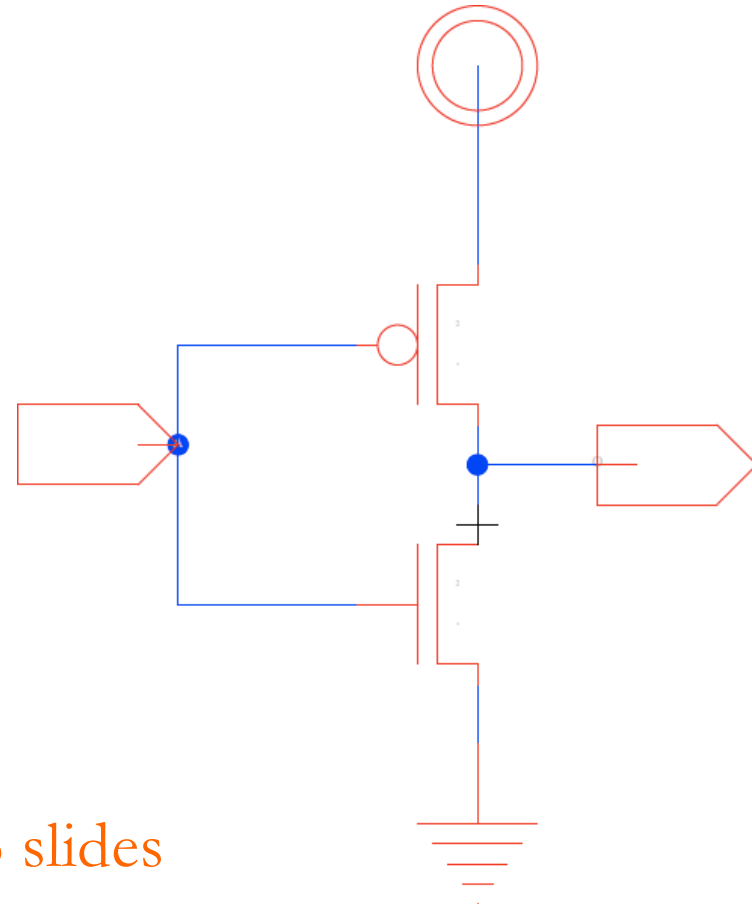
■ 500mV

■ 600mV

■ 860mV

■ 1V

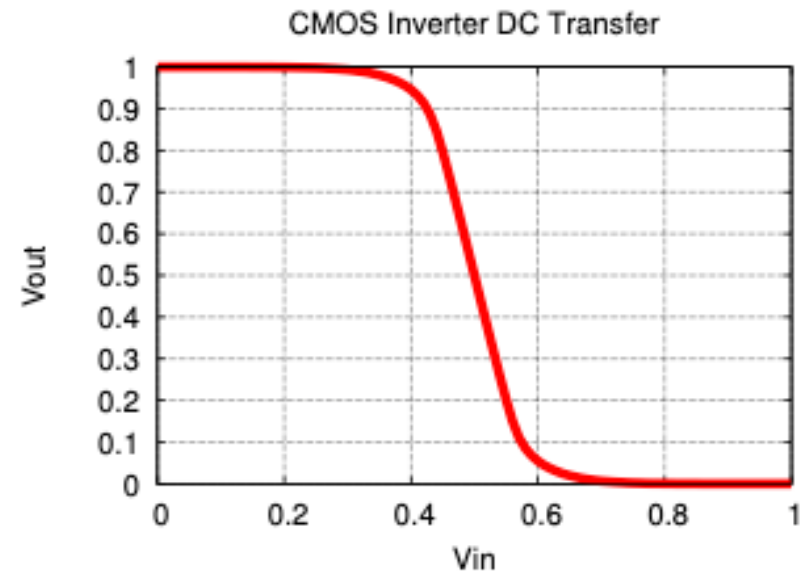
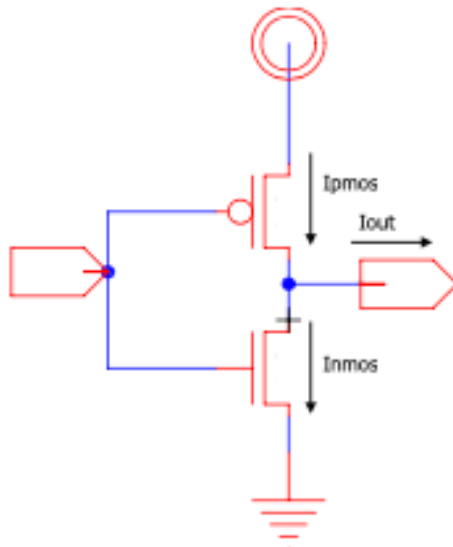
■ From preclass – see next two slides



Preclass 1

Device	V_{gs}	I_d
NMOS	$V_{gs} < V_{thn}$	$(3 \times 10^{-7}) e^{\frac{V_{gs} - V_{thn}}{40mV}}$
	$V_{gs} > V_{thn}$	$1.8 \times 10^{-4} (V_{gs} - V_{thn})$
PMOS	$V_{gs} > V_{thp}$	$(3 \times 10^{-7}) e^{-\left(\frac{V_{gs} - V_{thp}}{40mV}\right)}$
	$V_{gs} < V_{thp}$	$-1.8 \times 10^{-4} (V_{gs} - V_{thp})$

Consider an inverter:



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1. $V_{dd}=1V$, $V_{thn}=300mV$, $V_{thp}=-300mV$,

V_{in}	I_{pmos}	I_{nmos}	$\approx I_{pwr,gnd}$	
0V				A
140mV				B
400mV				C
500mV				D
600mV				E
860mV				F
1V				G

Approximate $I_{pwr,gnd} \approx \min(I_{nmos}, I_{pmos})$.

Useful: $e^{-1} \approx 0.37$, $e^{-4} \approx 0.02$, $e^{-7.5} \approx 6 \times 10^{-4}$,

Preclass 1

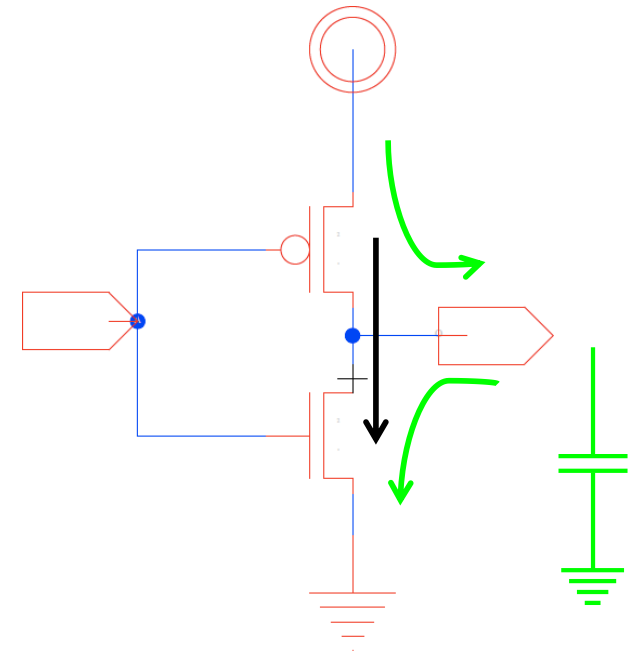
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A
B
C
D
E
F
G

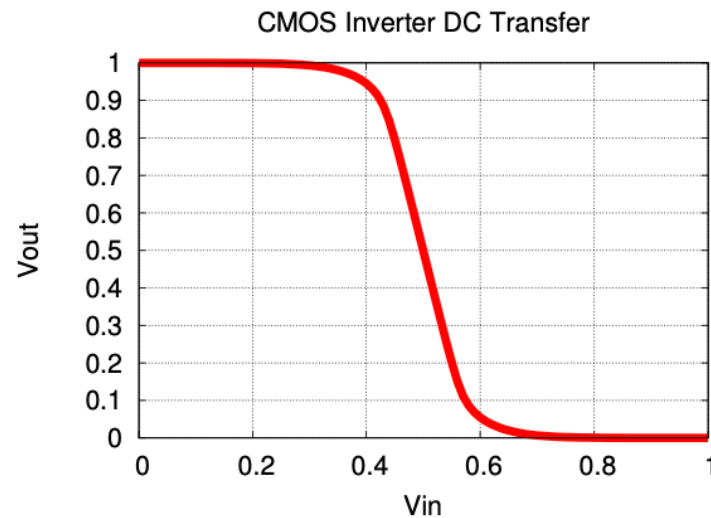
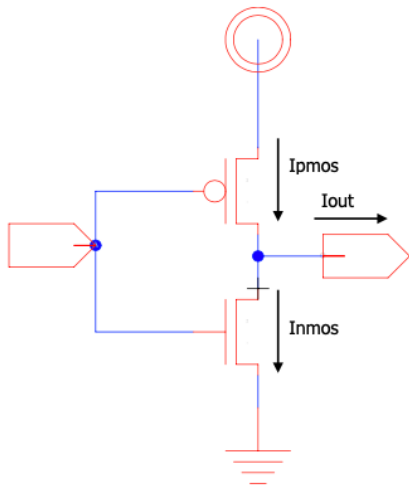
Approximate $I_{pwr,gnd} \approx \min(I_{nmos}, I_{pmos})$.



Preclass 2

Device	V_{gs}	V_{ds}	I_d
NMOS	$V_{gs} < V_{thn}$	any	$(3 \times 10^{-7}) e^{\frac{V_{gs} - V_{thn}}{40mV}}$
	$V_{gs} > V_{thn}$	$V_{ds} < V_{gs} - V_{thn}$	$3.6 \times 10^{-4} (V_{gs} - V_{thn}) \times V_{ds}$
		$V_{ds} > V_{gs} - V_{thn}$	$1.8 \times 10^{-4} (V_{gs} - V_{thn})$
PMOS	$V_{gs} > V_{thp}$	any	$(3 \times 10^{-7}) e^{-\left(\frac{V_{gs} - V_{thp}}{40mV}\right)}$
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2. $V_{dd}=1V$, $V_{thn}=300mV$, $V_{thp}=-300mV$, assume steady-state operation at V_{in} given.

V_{in}	$I_{pmos} = I_{nmos} = I_{pwr,gnd}$	Vout	
0V			A
140mV			B
400mV			C
500mV			D
600mV			E
860mV			F
1V			G

Approximate $I_{pwr,gnd} \approx \min(I_{nmos}, I_{pmos})$.

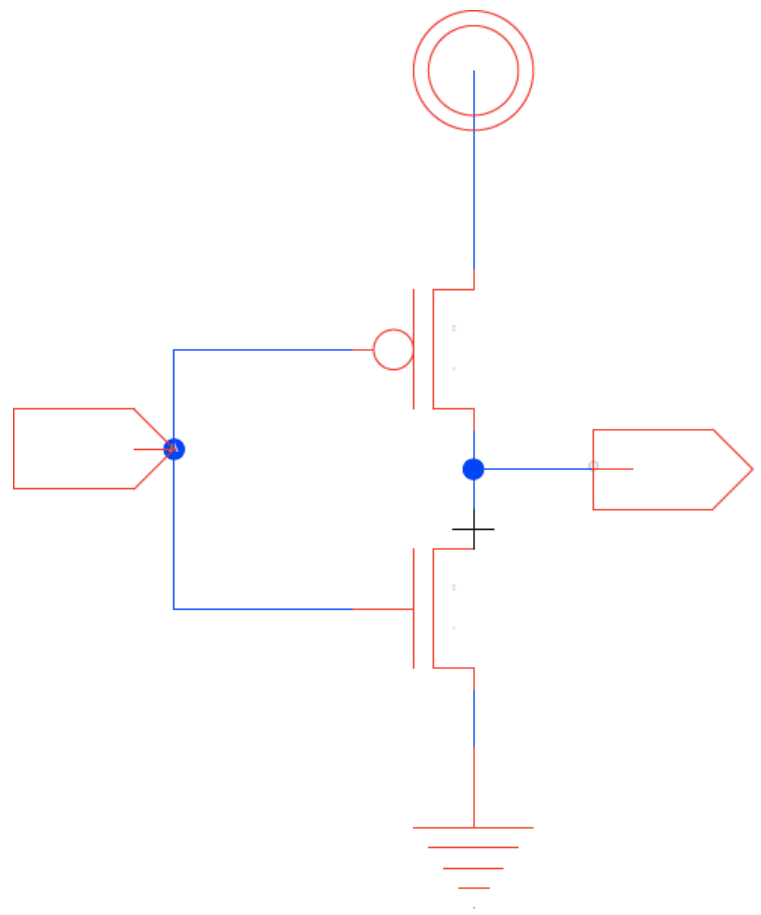
Understanding Currents

Static Power



Operating Modes

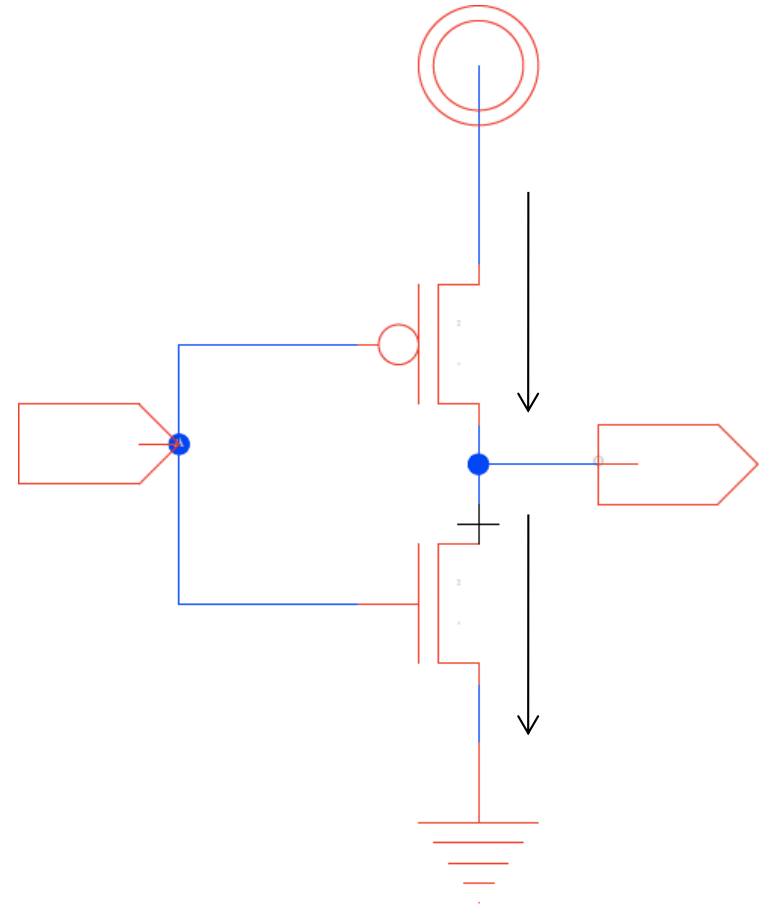
- ❑ Steady-State: What modes are the transistors in?
 - $V_{in} = V_{dd}$
 - $V_{in} = Gnd$
- ❑ What current flows in steady state?





Operating Modes

- Steady-State: $V_{in} = V_{dd}$
 - PMOS: subthreshold
 - NMOS: resistive

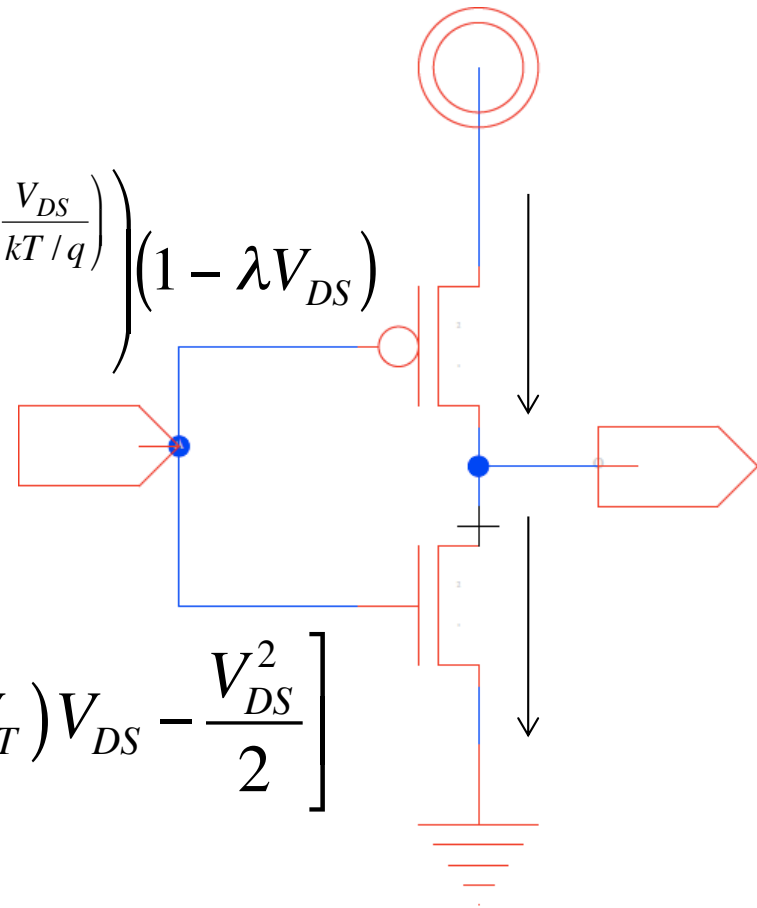


Operating Modes

- Steady-State: $V_{in} = V_{dd}$
 - PMOS: subthreshold
 - NMOS: resistive

$$I_{DSp} = -I_S' \left(\frac{W}{L} \right) e^{-\left(\frac{V_{GS} - V_T}{nkT/q} \right)} \left(1 - e^{\left(\frac{V_{DS}}{kT/q} \right)} \right) (1 - \lambda V_{DS})$$

$$I_{DSn} = \mu_n C_{OX} \left(\frac{W}{L} \right) \left[(V_{GS} - V_T) V_{DS} - \frac{V_{DS}^2}{2} \right]$$

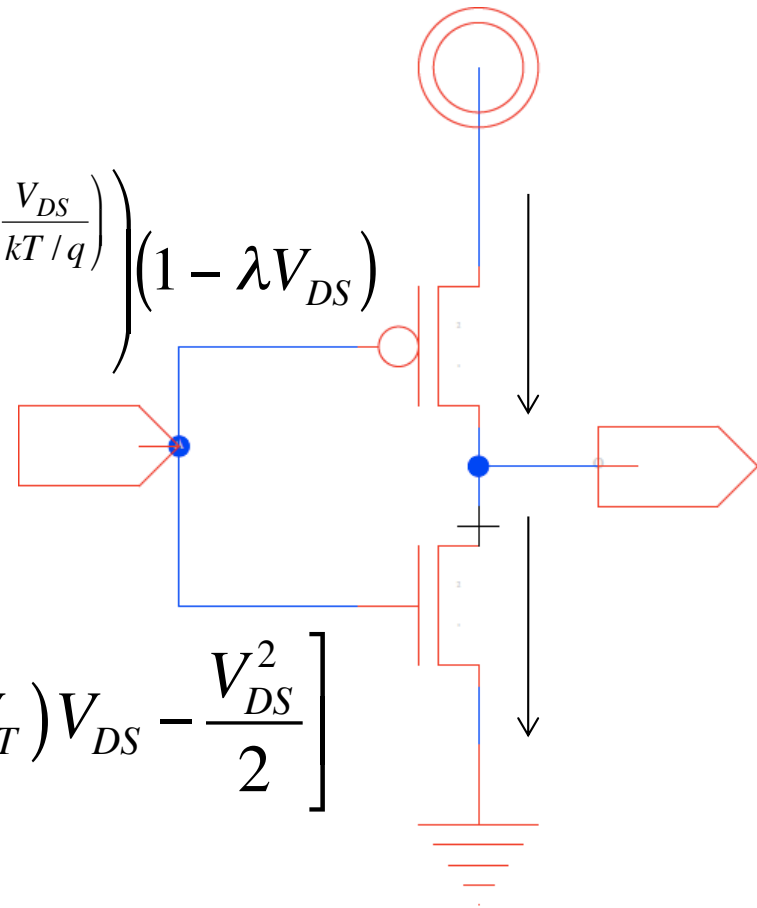


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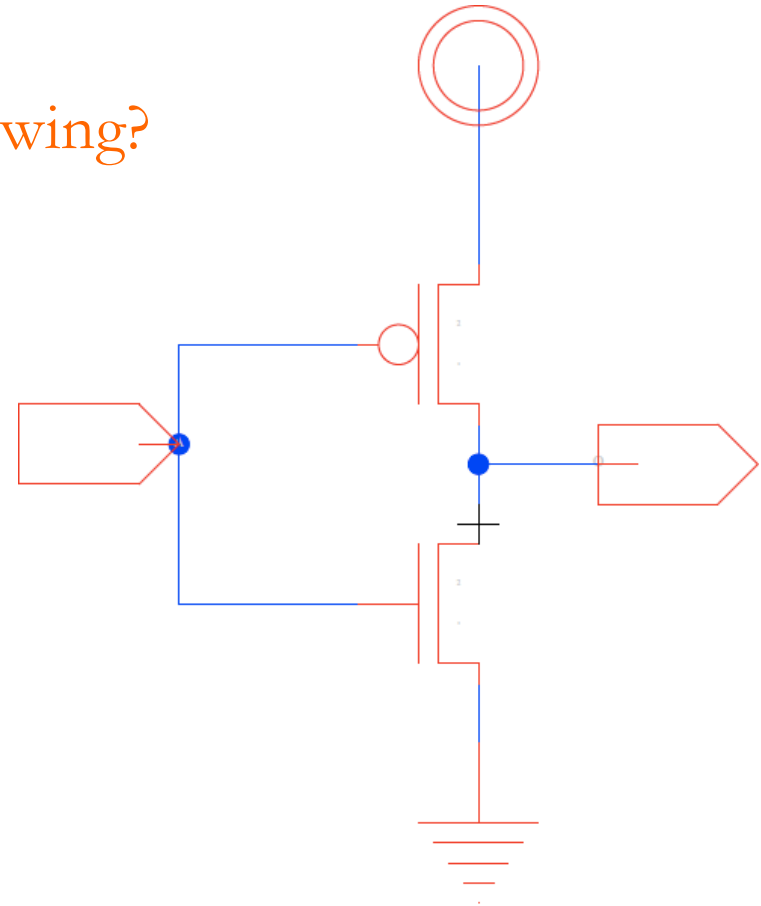


Which current determines I_{static} ?



Static Power

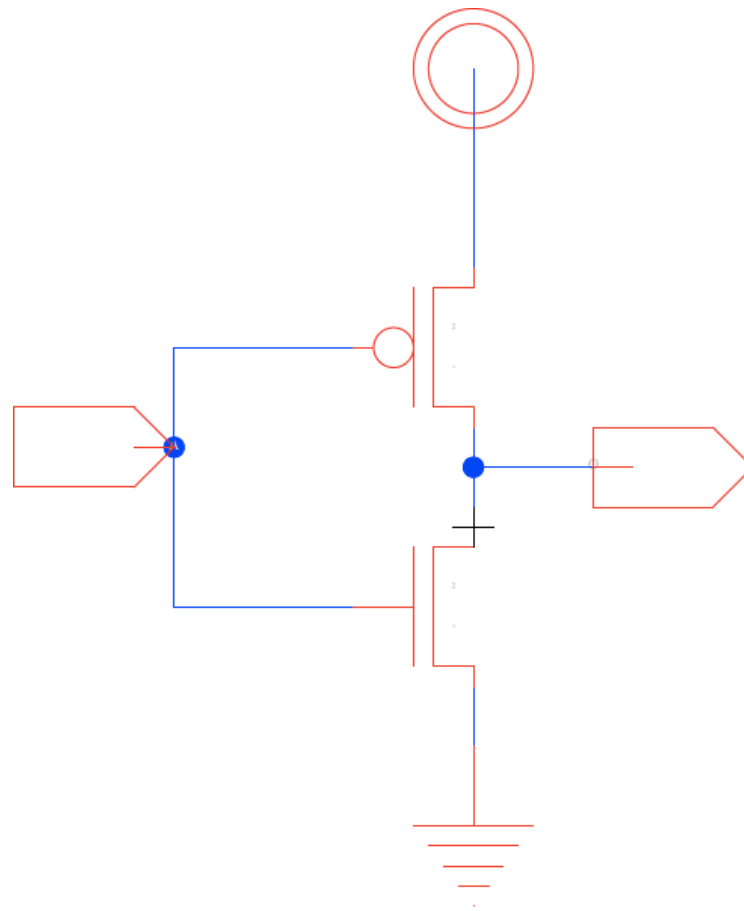
- $P = I \times V$
- What V should we use?
 - Where is the static current flowing?





Data Dependent?

- How does the binary value of the input impact I_{static} ?

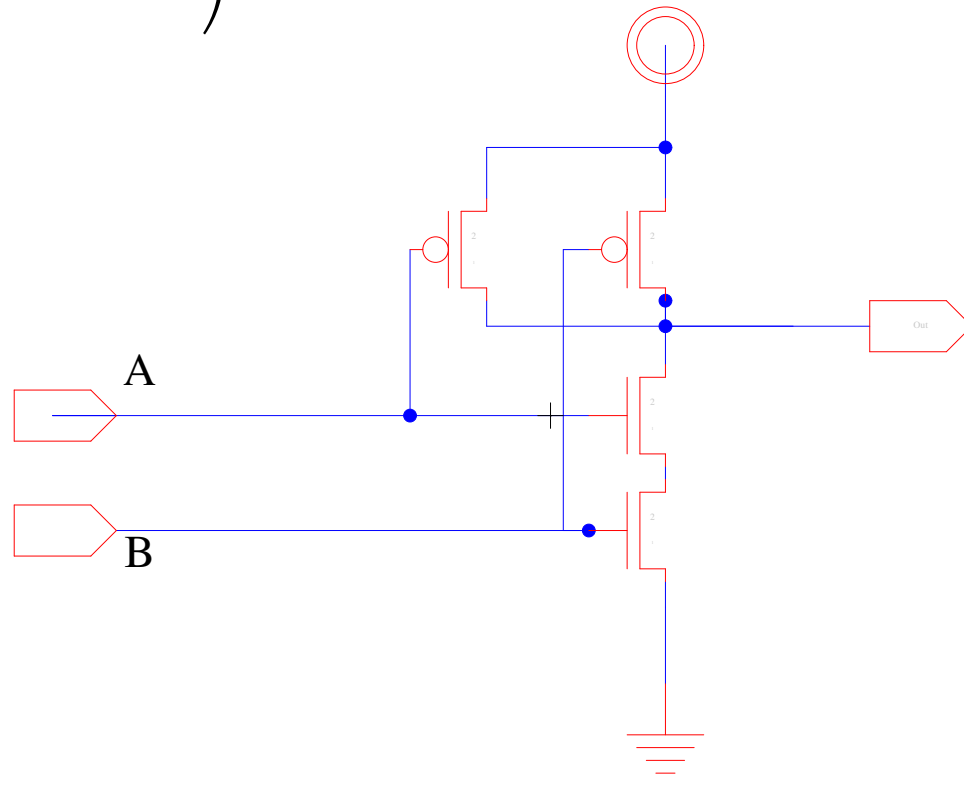




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Data Dependent Leakage Current

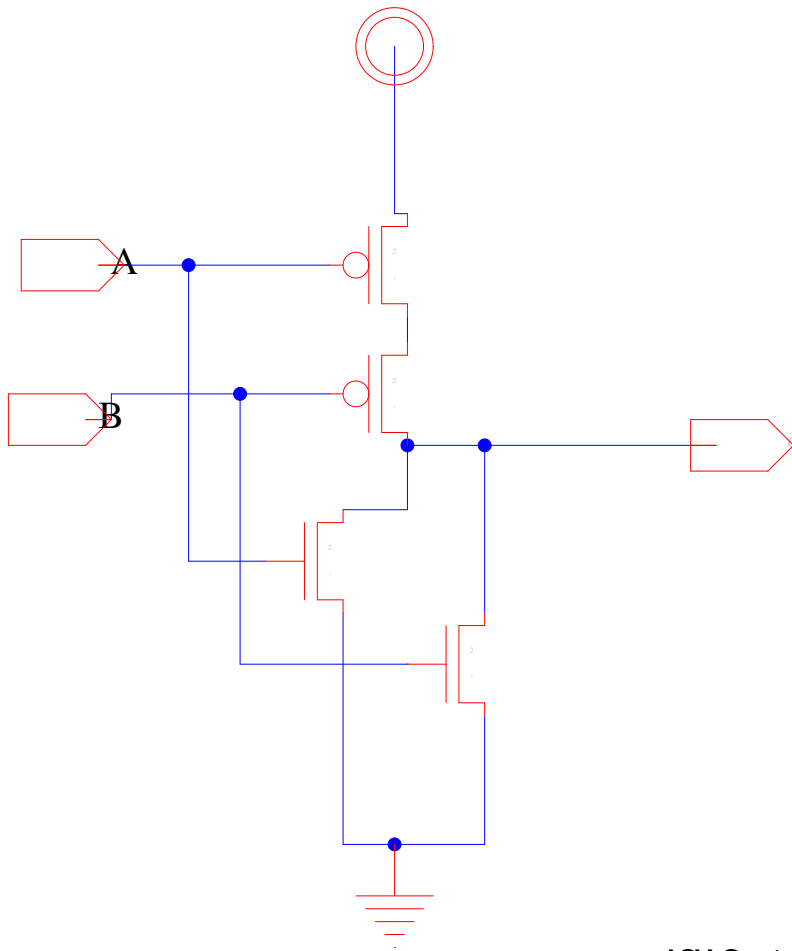


Table 1. Standard CMOS Gates Leakage Currents

		Temp °C	0	25	50	75	100
		Logic Lv.	Leakage Current (T°) [pA] @ 1,2 Vdd				
NOT	0		65,9	163,9	353,9	682,9	1203,9
	1		4,4	10,4	23,5	49,0	93,3
NOR	00		131,9	327,7	707,9	1365,8	2405,7
	01		4,4	10,4	23,5	48,1	90,1
	10		6,2	11,8	24,1	49,0	93,3
	11		2,3	4,4	9,3	19,3	37,4
NAND	00		9,4	24,5	57,5	120,9	231,2
	01		65,9	163,9	353,9	682,9	1202,8
	10		52,0	128,4	279,7	545,8	972,8
	11		8,8	20,7	47,1	98,0	186,6
XOR	00		258,7	640,8	1388,7	2692,5	4768,1
	01		154,5	383,4	836,0	1633,8	2916,9
	10		140,6	347,9	761,8	1496,7	2686,9
	11		135,6	333,8	727,8	1424,7	2549,0

ACM Great Lakes Symposium on VLSI Stresa, I. (n.d.). Analysis of data dependence of leakage current in CMOS cryptographic hardware. In GLSVLSI '07 proceedings of the 2007 ACM Great Lakes Symposium on VLSI : Stresa - Lago Maggiore, Italy, March 11-13, 2007 /. New York, N.Y. :: Association for Computing Machinery. <https://doi.org/10.1145/1228784.1228808>

Data Dependent Leakage Current

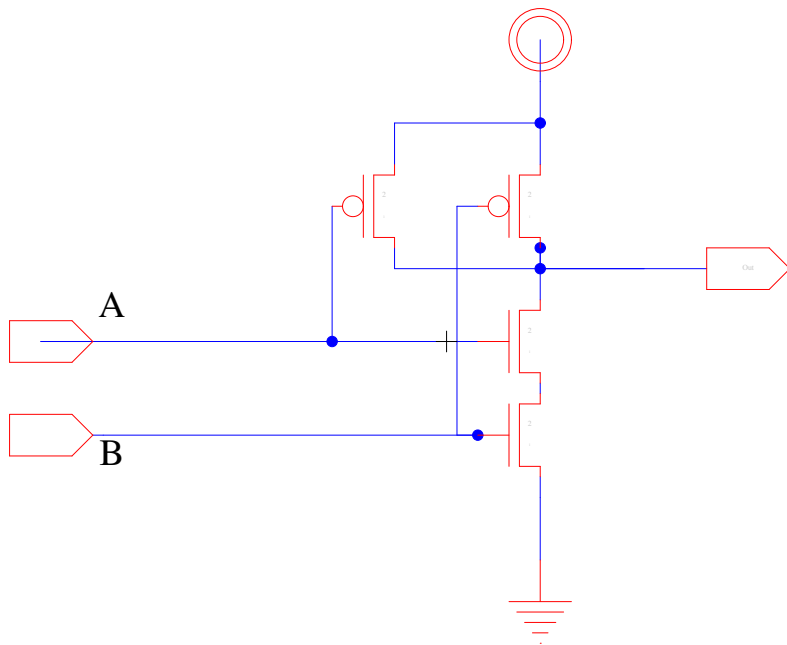


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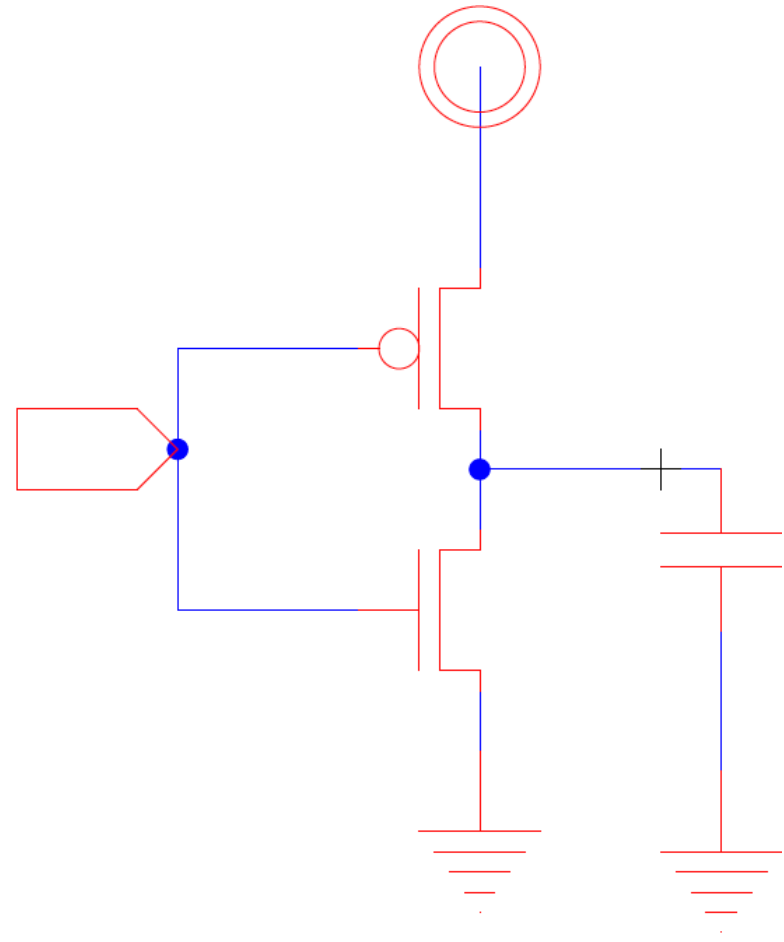
Understanding Currents

Dynamic Switching Currents



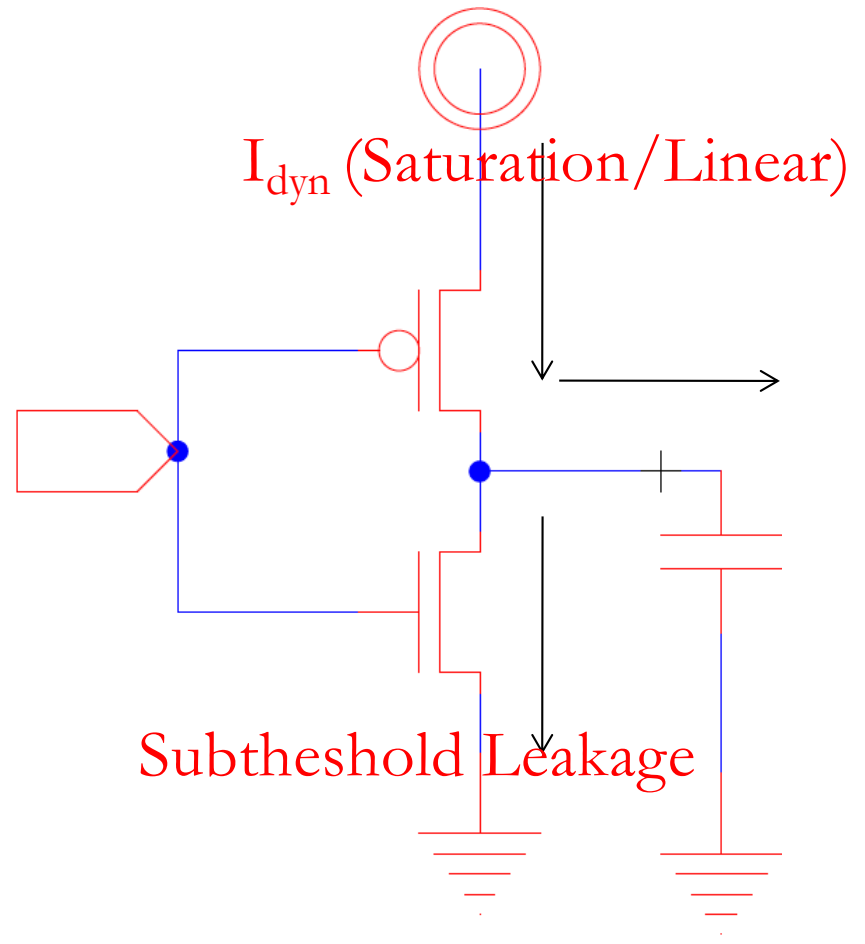
Power: During Switching

- $P = IV$
- Input switch: $1 \rightarrow 0$
- Where does I go?
 - $V_{in} = \text{Gnd}$



Power: During Switching

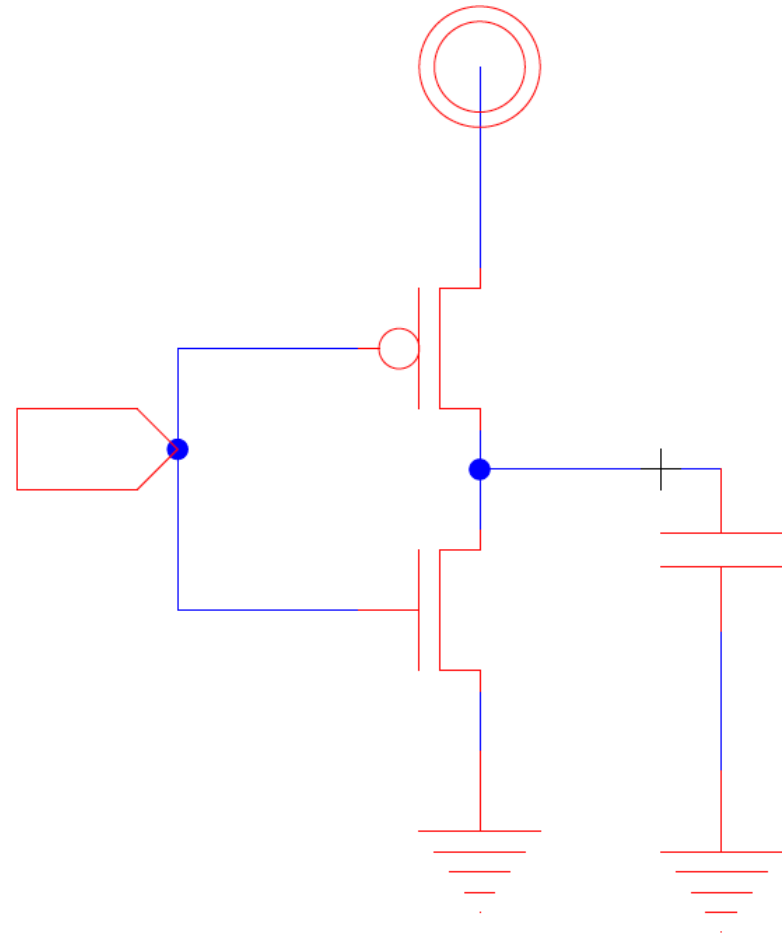
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- Input switch: $1 \rightarrow 0$
- Where does I go?
 - $V_{in} = \text{Gnd}$





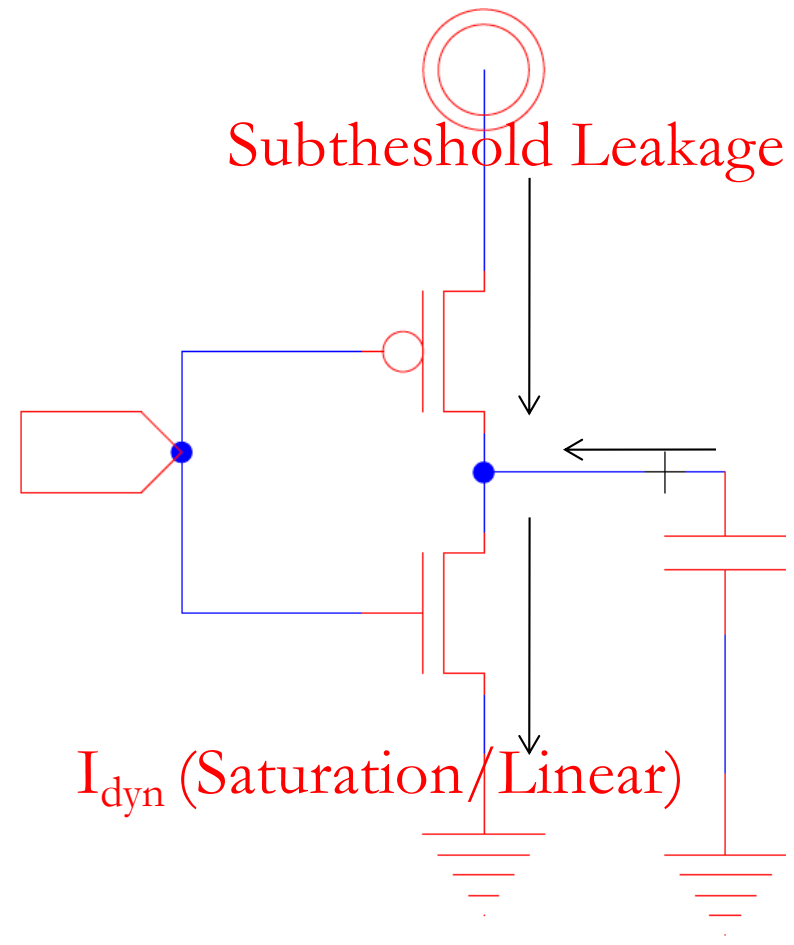
Power: During Switching

- $P = IV$
- Input switch $0 \rightarrow 1$
- Where does I go?
 - $V_{in} = V_{dd}$



Power: During Switching

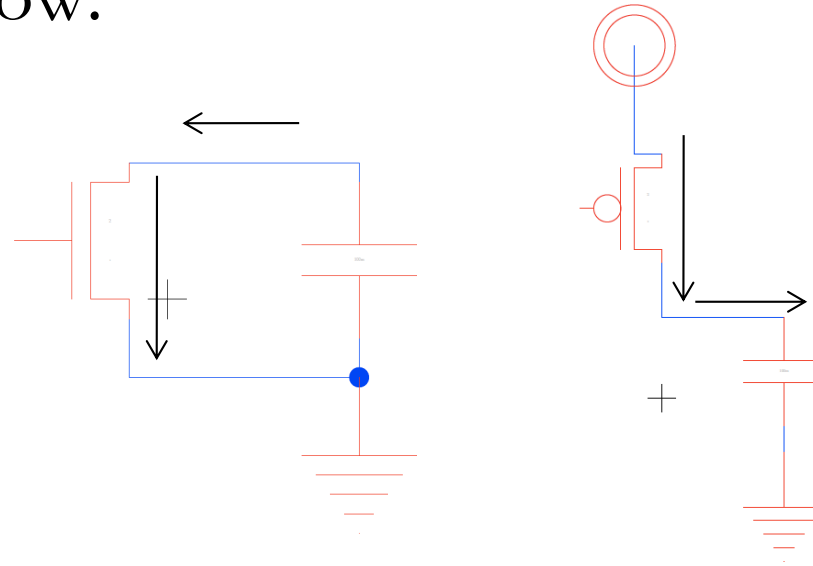
- $P = IV$
- Input switch $0 \rightarrow 1$
- Where does I go?
 - $V_{in} = V_{dd}$





Switching Currents

- Dynamic current flow:

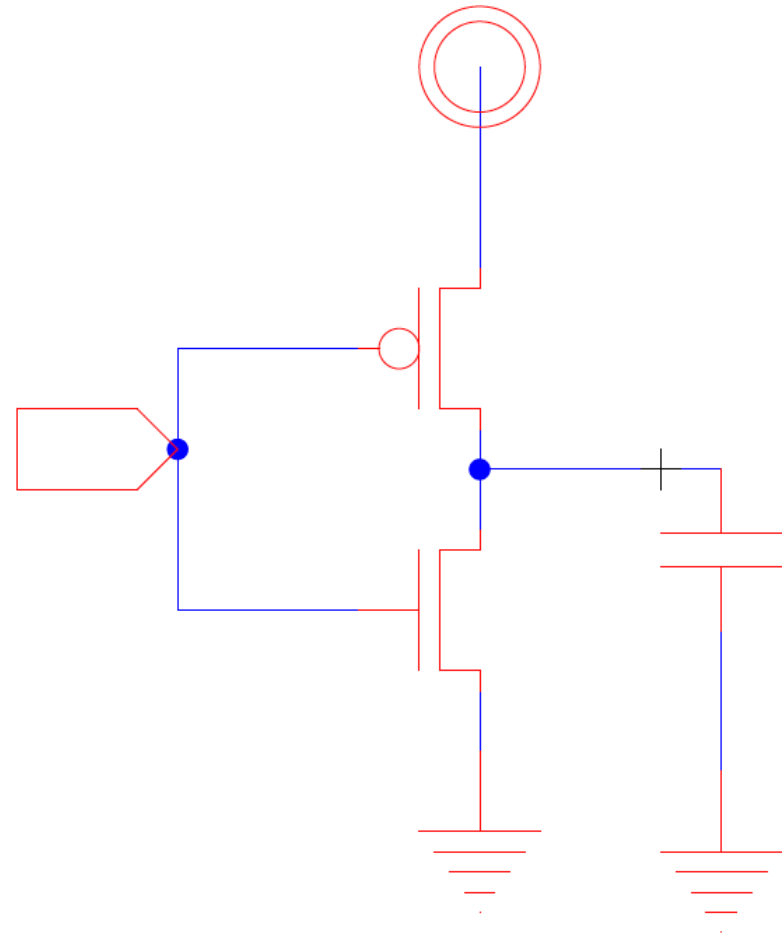


Understanding Currents

Short Circuit Currents

Power: During Switching

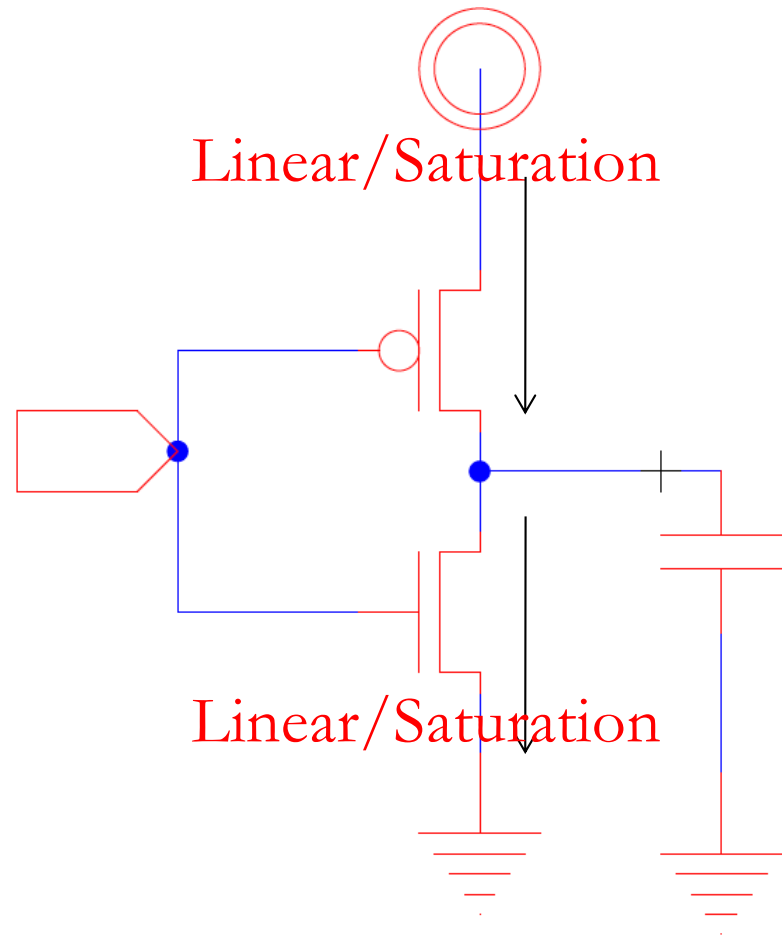
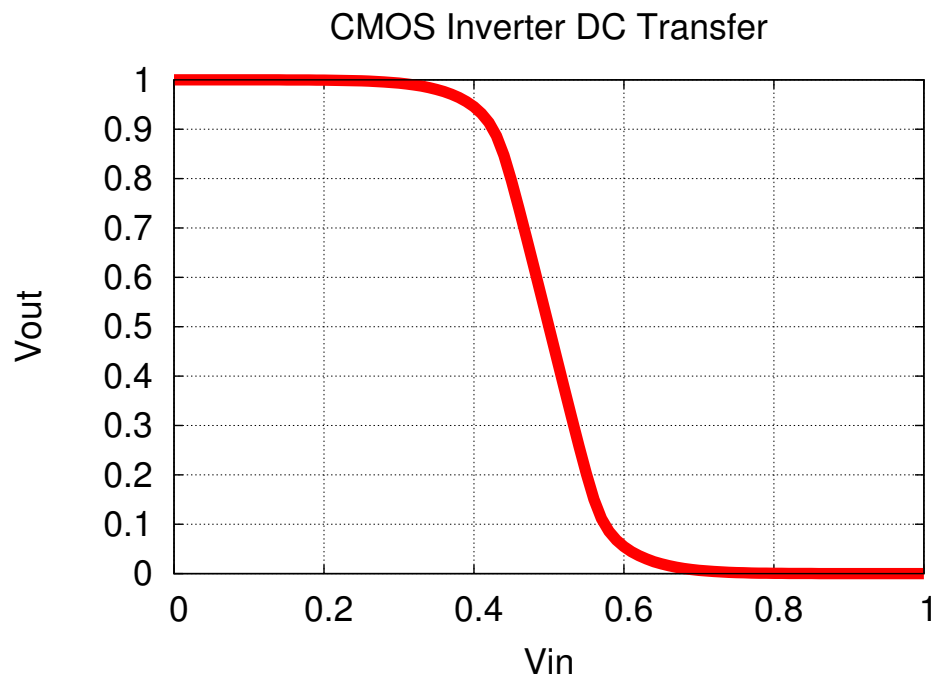
- $P = IV$
- Where does I go?
 - $V_{in} = V_{dd}/2$
 - And $V_{dd} > V_{thn} + |V_{thp}|$





Power: During Switching

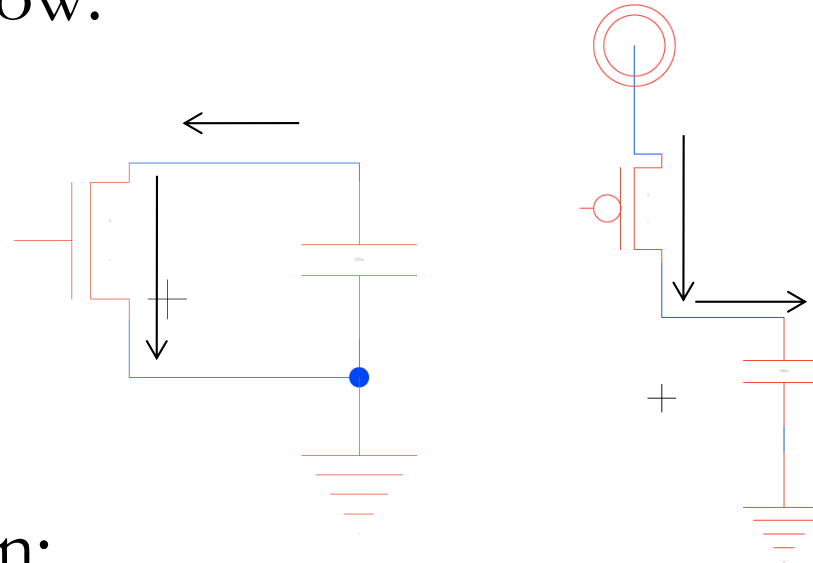
- $P = IV$
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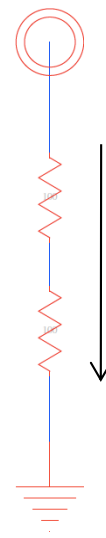
Switching Currents

□ Dynamic current flow:



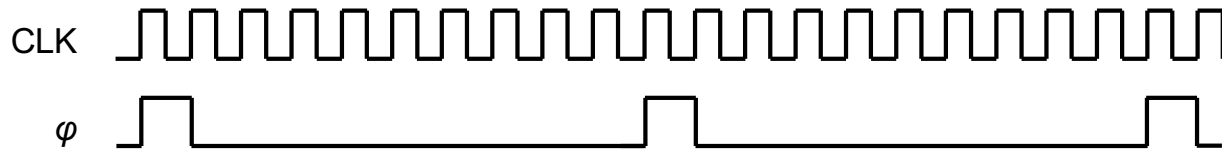
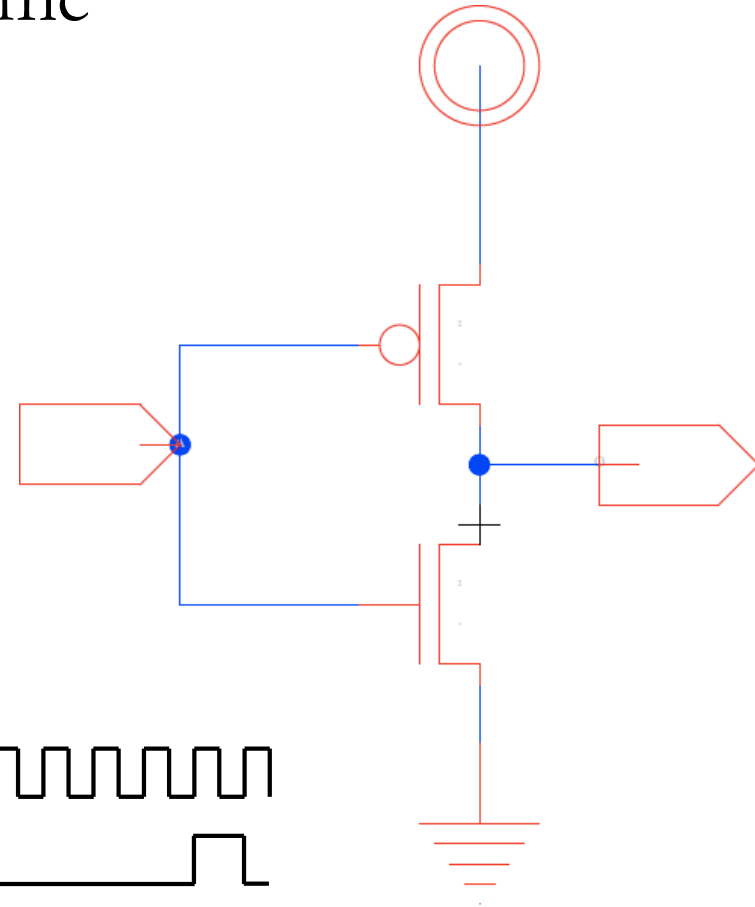
□ If both transistor on:

- Current path from V_{dd} to Gnd
- Short circuit current



Currents Summary

- ❑ Current (I) changes over time
- ❑ At least two components
 - I_{static} – no switching
 - I_{switch} – when switching
 - I_{dyn} and I_{sc}



Switching

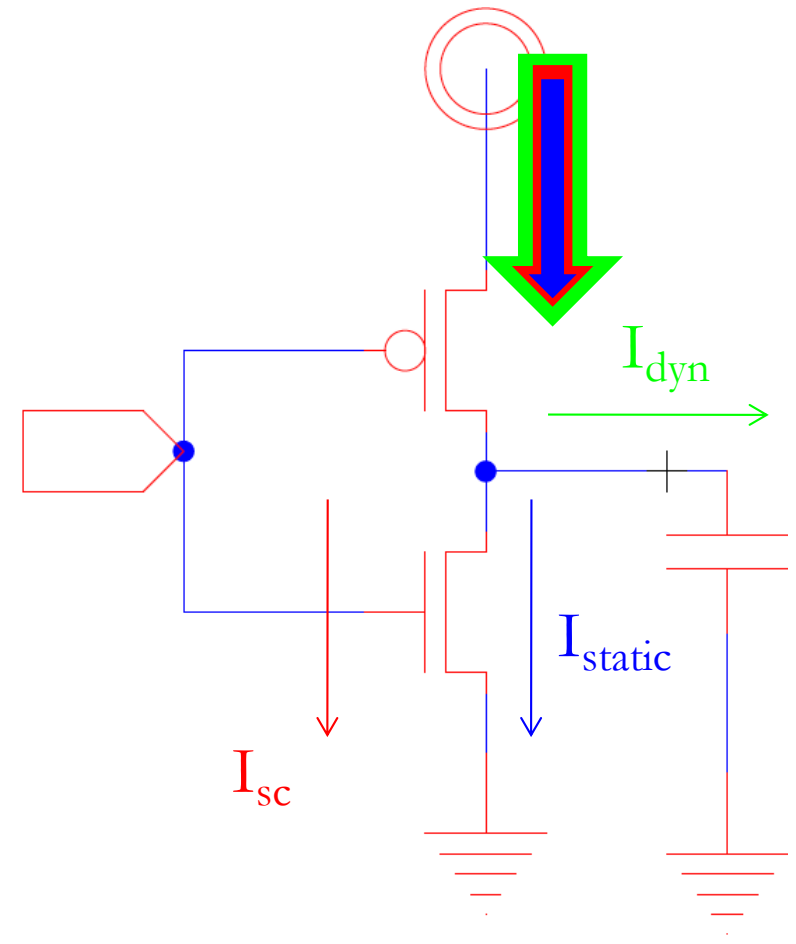
Dynamic Power



Switching Currents

□ $I_{total}(t) = I_{static}(t) + I_{switch}(t)$

□ $I_{switch}(t) = I_{sc}(t) + I_{dyn}(t)$

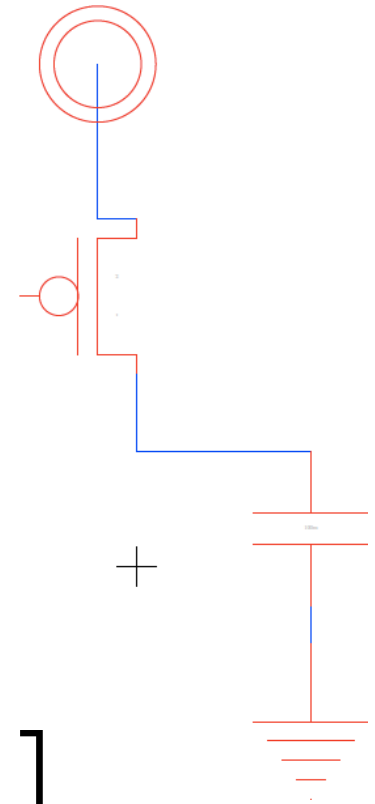


Charging

□ $I_{dyn}(t)$ – why is it changing?

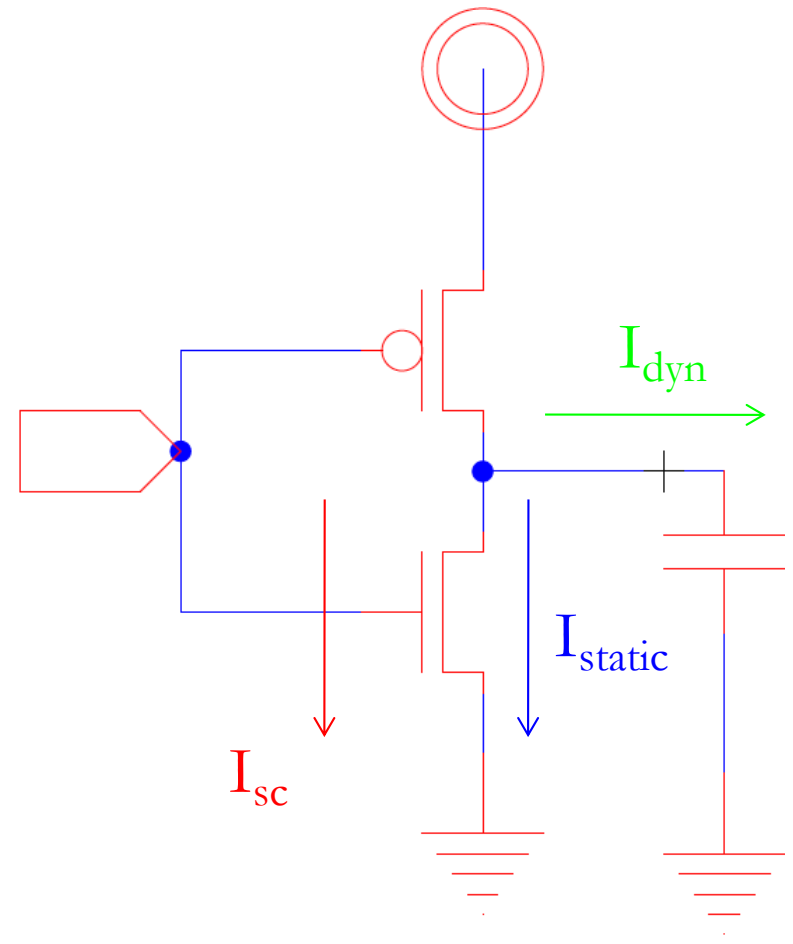
- $I_{ds} = f(V_{ds}, V_{gs})$
- and V_{gs} , V_{ds} changing

$$I_{DS} \approx v_{sat} C_{OX} W \left(V_{GS} - V_T - \frac{V_{DSAT}}{2} \right)$$
$$I_{DS} = \mu_n C_{OX} \left(\frac{W}{L} \right) \left[(V_{GS} - V_T) V_{DS} - \frac{V_{DS}^2}{2} \right]$$



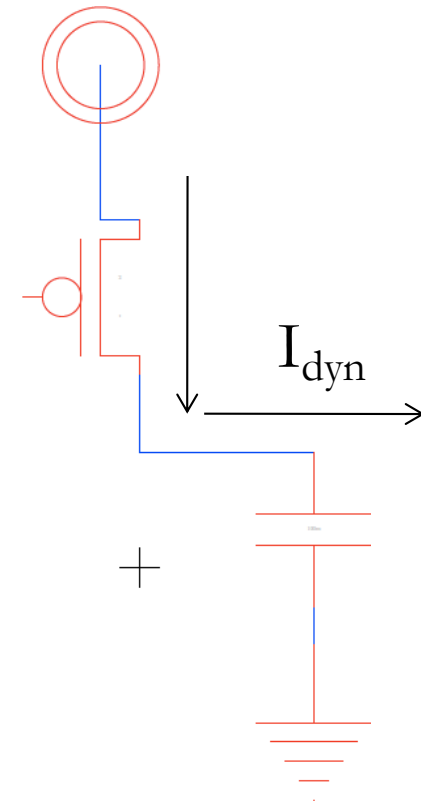


Switching Energy – focus on $I_{dyn}(t)$



Switching Energy – focus on $I_{dyn}(t)$

$$\begin{aligned} E &= \int P(t) dt \\ &= \int I(t) V_{dd} dt \\ &= V_{dd} \int I(t) dt \end{aligned}$$



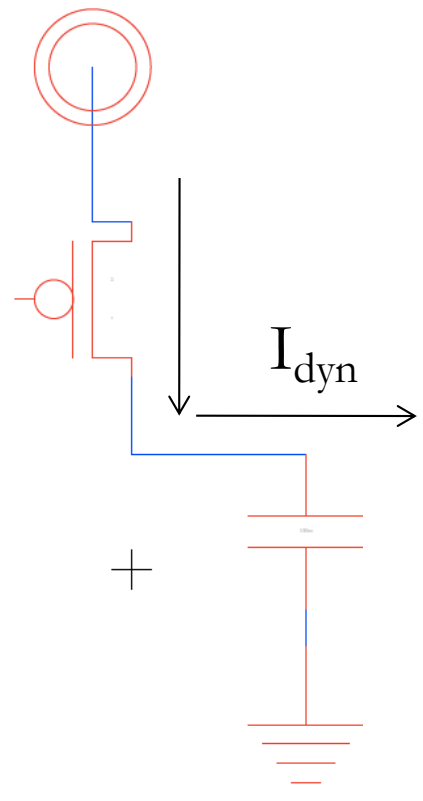


Switching Energy

□ Do we know what this is?

$$\int I_{dyn}(t) dt$$

$$\begin{aligned} E &= \int P(t) dt \\ &= \int I(t) V_{dd} dt \\ &= V_{dd} \int I(t) dt \end{aligned}$$



Switching Energy

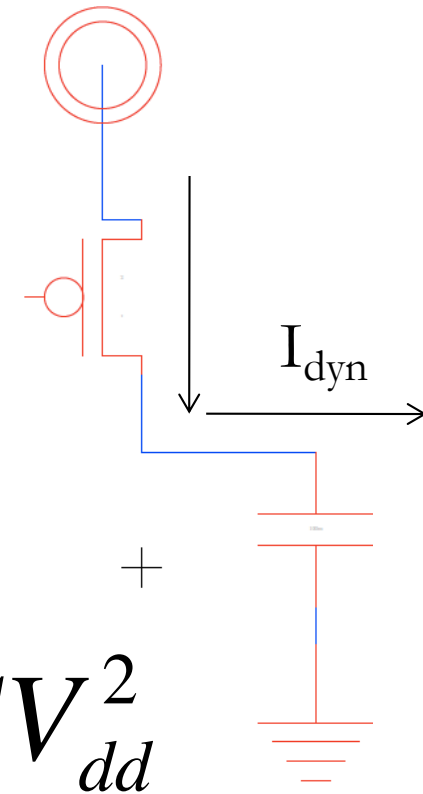
- Do we know what this is?

$$Q = \int I_{dyn}(t) dt$$
$$= CV$$

$$E = \int P(t) dt$$
$$= \int I(t)V_{dd} dt$$
$$= V_{dd} \int I(t) dt$$



$$E = CV_{dd}^2$$



Capacitor charging energy



Switching Power

- Every time output switches $0 \rightarrow 1$ pay:
 - $E = CV^2$
- $P_{\text{dyn}} = (\# 0 \rightarrow 1 \text{ trans}) \times CV^2 / \text{time}$
- $\# 0 \rightarrow 1 \text{ trans} = 1/2 \# \text{ of transitions}$
- $P_{\text{dyn}} = (\# \text{ trans}) \times 1/2 CV^2 / \text{time}$



Charging Power

- ❑ $P_{\text{dyn}} = (\#0 \rightarrow 1 \text{ trans}) \times CV^2 / \text{time}$
- ❑ Often like to think about switching frequency
- ❑ Useful to consider per clock cycle
 - Frequency $f = 1/\text{clock-period} = \text{clock-cycles}/\text{time}$
- ❑ $P_{\text{dyn}} = (\#0 \rightarrow 1 \text{ trans}/\text{clock-cycle}) CV^2 f$

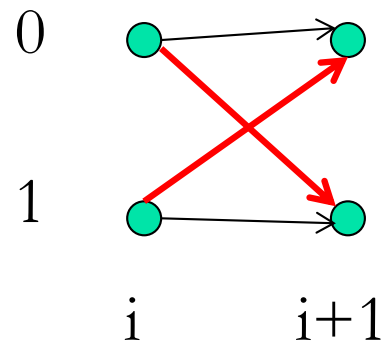


Data Dependent Activity

- Consider an 8b counter
 - How often do each of the following switch?
 - Low bit?
 - High bit?
- Assuming random inputs
 - Activity at output of nand2?
 - Activity at output of xor2?

Gate Output Switching (random inputs)

Output states



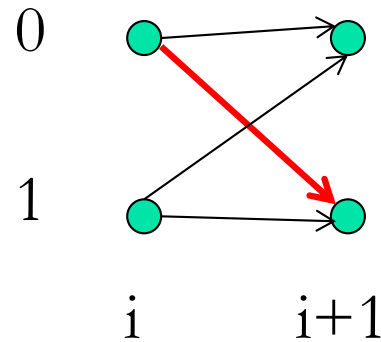
$$P(\text{out}_i \neq \text{out}_{i+1}) = P(\text{out}_i = 0) * P(\text{out}_{i+1} = 1) + P(\text{out}_i = 1) * P(\text{out}_{i+1} = 0)$$

Probability of output switch of nand2?

Probability of output switch of xor2?

Gate Output Switching (random inputs)

Output states



$$P(\text{out}_i \rightarrow \text{out}_{i+1} = 0 \rightarrow 1) = P(\text{out}_i = 0) * P(\text{out}_{i+1} = 1)$$



Dynamic Power

- $P_{\text{dyn}} = (\#0 \rightarrow 1 \text{ trans/clock-cycle}) CV^2 f$
- Let $a = \text{activity factor}$
 - $a = \text{average } \# \text{tran}_{0 \rightarrow 1} / \text{clock}$
 - $a = \text{probability of } \# \text{tran}_{0 \rightarrow 1}$

- $P_{\text{dyn}} = aCV^2 f$



Activity Factor

- Let a = activity factor
 - a = average #tran_{0→1}/clock
 - a = probability of #tran_{0→1}

$$a = p(out_i = 0)p(out_{i+1} = 1)$$

$$a = \frac{N_0}{2^N} \frac{N_1}{2^N} = \frac{N_0(2^N - N_0)}{2^{2N}}$$



Ideas

- Three components of power
 - Static
 - Dynamic
 - Short-circuit (next time)
- $P_{tot} = P_{static} + P_{dyn} + P_{sc}$



Admin

- HW 5 out now
 - A lot of SPICE
 - Start early
 - Create your schematics, icons and test schematics with care to minimize the time spent
 - Q 6 and 7 are extra credit